

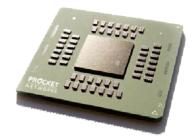
## output Adaptive Packet Processor (oAPP)



Olivia Wu Nikhil Jayaram

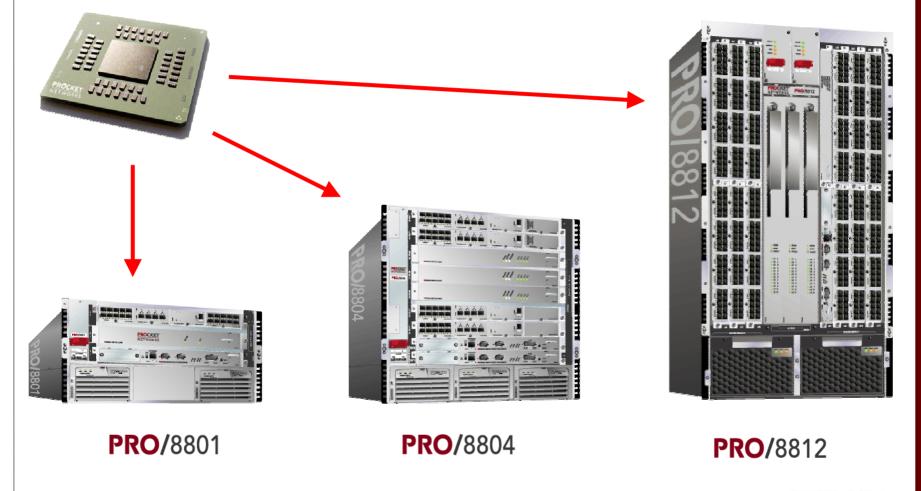
www.procket.com

## oAPP – output Adaptive Packet Processor



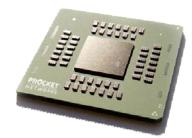


## oAPP – Shipping in PRO/8000 series





## oAPP – Agenda



## oAPP

- Features
- Top-Level
- Blocks
- Design challenges
- Design flow
- Q&A

### PRO/8812

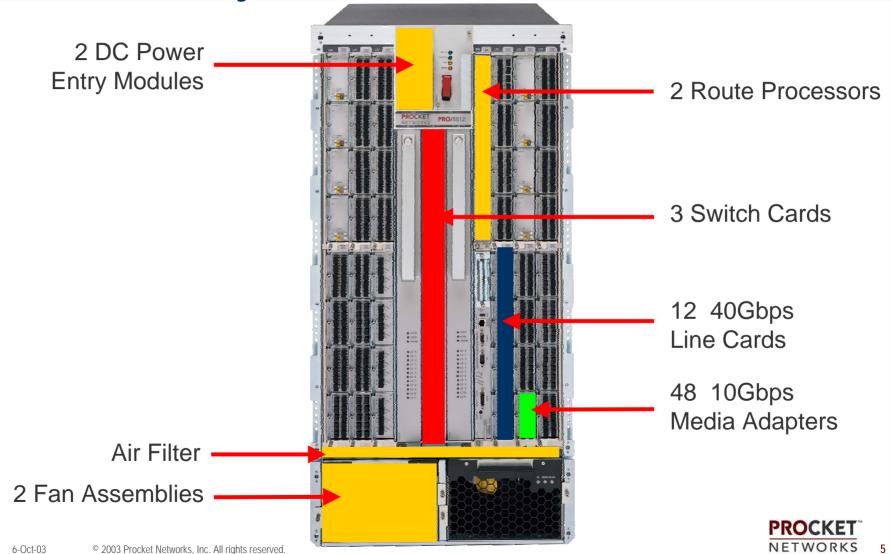
- System
- Architecture
- Key concepts



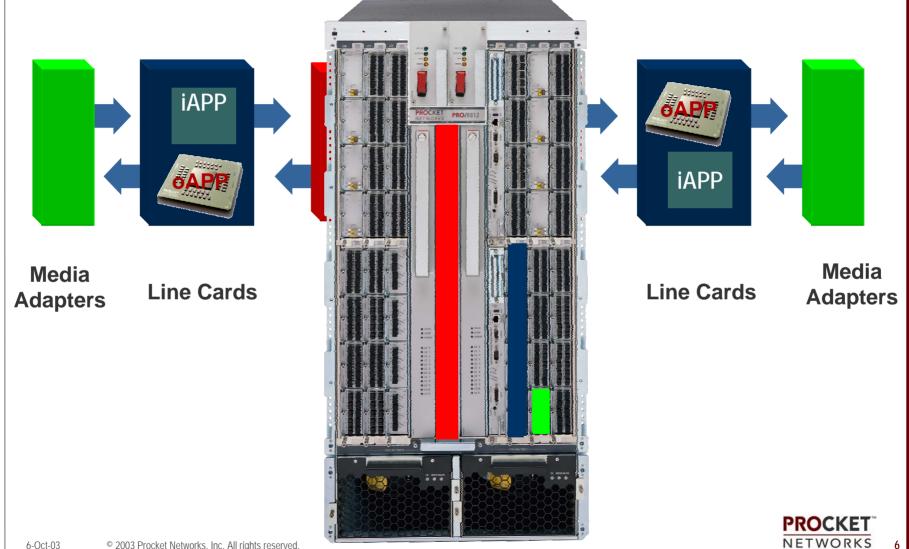




## PRO/8812 – System

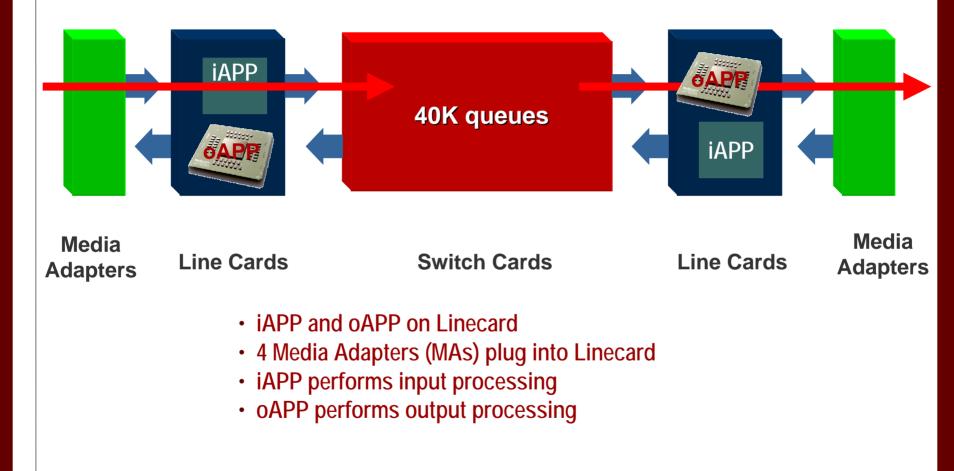


## PRO/8812 – Architecture



6

## PRO/8812 – Architecture





## oAPP

## High performance

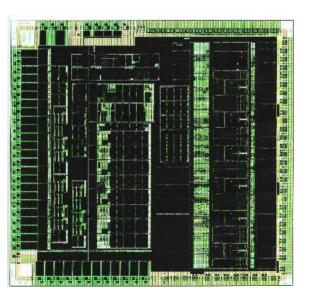
- 40 Gbps
- Non-blocking
- Traffic Management
- Encapsulation

## **Fully featured**

- Shaping
- Accounting
- *QoS*
- Multicast
- Fragmentation

#### Programmable

- QoS
- Encapsulation



## CAPP?

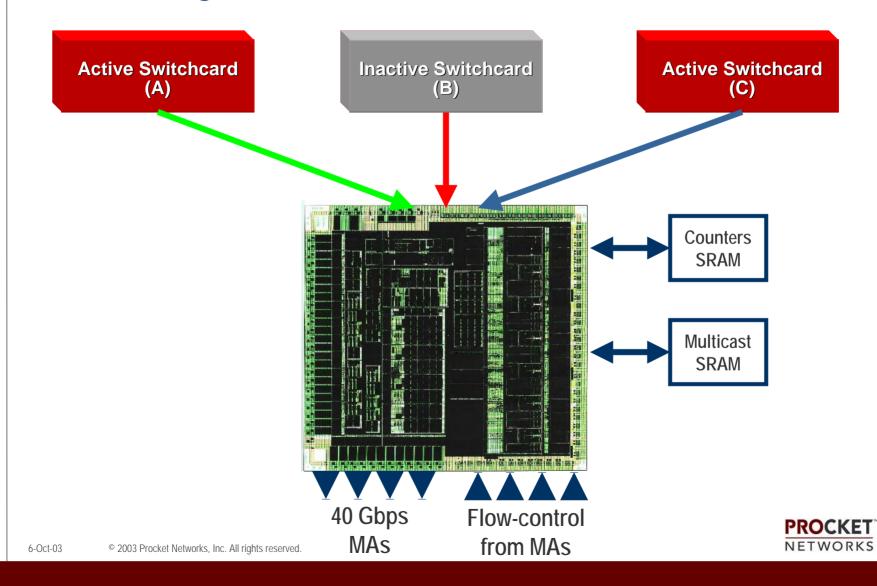
## Robust

- *OIR*
- BIST
- ECC/parity
- CRC24

## **Design challenges**

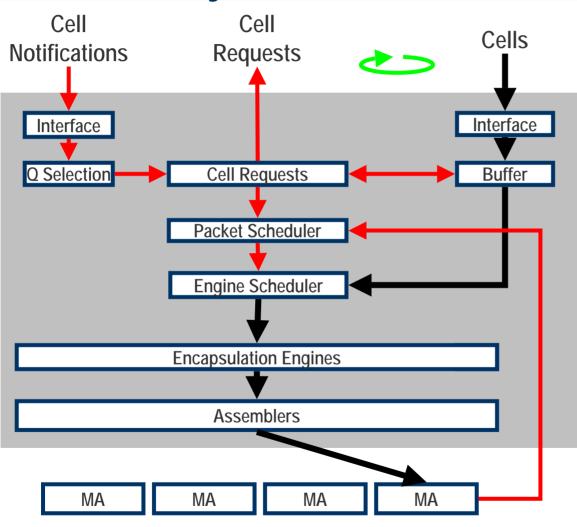


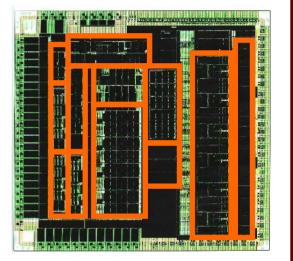
## oAPP – High Performance



9

## oAPP – Fully Featured



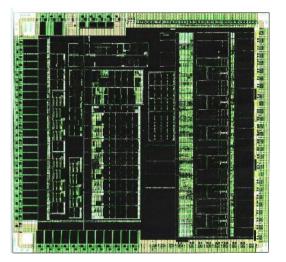




## oAPP – Fully Featured

#### Accounting

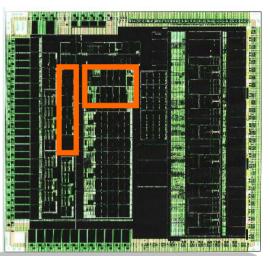
- Precise packets and bytes
- Per port
- RED drops
- Metering drops
- Multicast replication
- Fragmentation

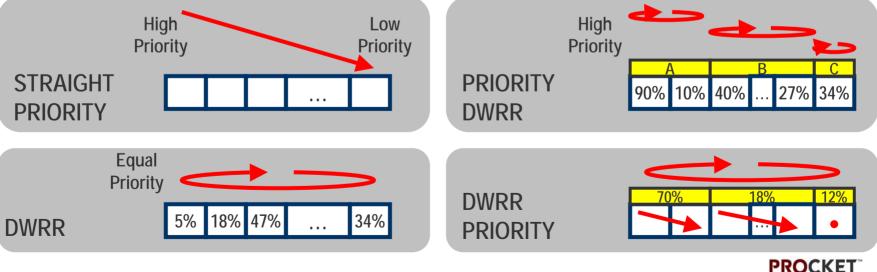




## oAPP Programmable – Queue Selection

- Queue and group-queue rate-shaping
- Selectable per interface
- Disciplines currently programmed:





NETWORKS

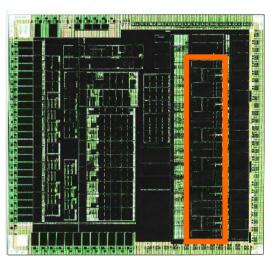
## oAPP Programmable – Encapsulation Engines

## Multiple Encapsulation Engines

- Fully programmable
- Easily add new encapsulations

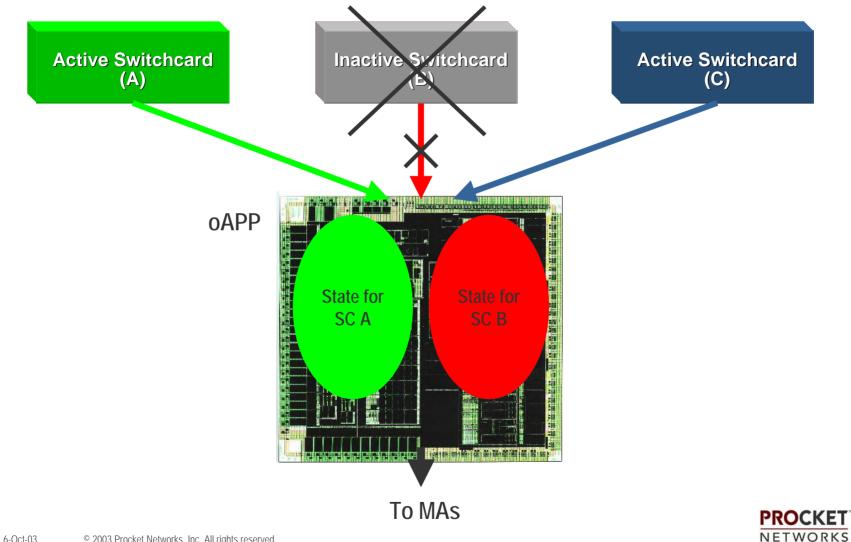
## Encapsulation engine

- Modifies packet
- L2 encapsulation
- Physical port identifier
- Send cells to Assembler





## oAPP Robustness – Switchcard Failover

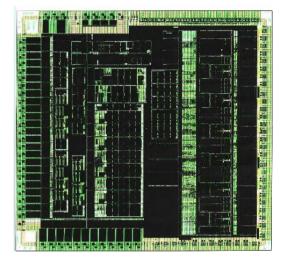


## oAPP Robustness – Reliability

### • ECC/parity

- On-chip SRAM
- Off-chip SRAM
- BIST & repair
- End-to-end packet CRC-24
- Inter-chip
  - CRC
  - Parity
  - ECC

## Internal consistency checks





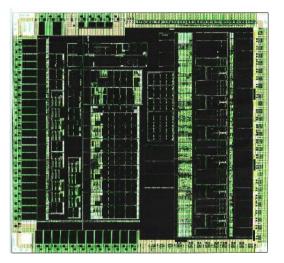
## oAPP Design Challenges

#### Speed

- 40Gbps
- 100+ Mpps
- 350 MHz
- 0.18um copper CMOS
- Scale
  - Programmable engines
  - 950KBytes SRAM
  - 137M transistors
  - 425 sq mm

#### Analog

- 170 2.5 GHz serial links
- Multiple clock domains
- Power





## oAPP Design Challenges – ASIC

#### Speed

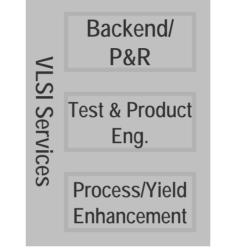
- 40Gbps
- 100+ Mpps
- 350 MHz
- 0.18um copper CMOS

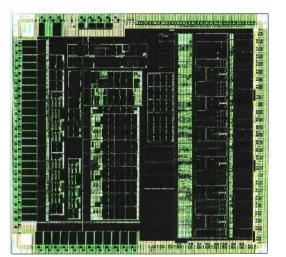
#### Scale

- Programmable engines
- 950KBytes SRAM
- 137M transistors
- 425 sq mm

#### Analog

- 170 2.5 GHz serial links
- Multiple clock domains
- Power







## oAPP Design Challenges – COT

#### • Speed

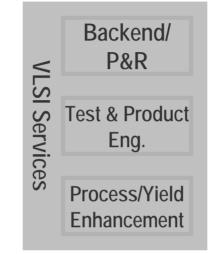
- 40Gbps
- 100+ Mpps
- 350 MHz
- 0.18um copper CMOS

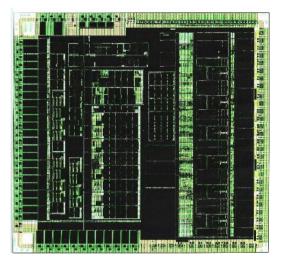
#### Scale

- Programmable engines
- 950KBytes SRAM
- 137M transistors
- 425 sq mm

#### Analog

- 170 2.5 GHz serial links
- Multiple clock domains
- Power efficient

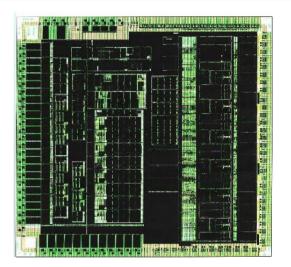






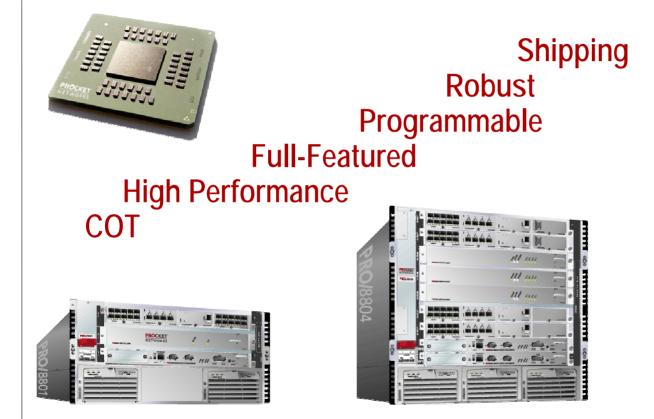


## oAPP Design Challenges – COT





## oAPP – Summary



**PRO/**8804



**PRO/**8812



**PRO/**8801

## PROCKET<sup>M</sup> NETWORKS

**VLSI IP & Expertise** 

System/Chip Architecture

Design/ Verification

# **VLSI** Services





## 2.5 GHZ Serial Links in 0.18 and 0.13 um

- Source synchronous
- very low BER
- 48 inches backplane trace + 2 connectors
- Multilink bundling
- Low power (<200mW in 0.18 um)
- oAPP has 170 links other Procket chips more than 250

<	
S	
S	
er	
<	
Vic	
ces	
S	





## High-performance embedded SRAM

- Creation of any configuration
- 500MHz designs achieved in 0.18
  - 2-port and 4-port
- *Row/column redundancy* 
  - RAMBist design for test and reliability

<
<u>I</u>
S
er
$\leq$
ces





## Standard-Cell and IO Library Design

- *High speed/low power FFs*
- Automated RTL to I/O Frame generation
- Proprietary clock distribution
  - reduced power and clock skew

VLSI Services





#### Packaging

- Flip-Chip CGA, HITCE glass ceramic
  - 16 GHz bandwidth
  - 58 mm. Body size
  - 20 layers
- HiTCE improves reliability
- In-house automated design

**VLSI Services** 





## Backend/P&R:

- Customize around standard tools
- Internal development where necessary
- Custom clock distribution
- RTL freeze to GDS TO in 2 weeks!
- ECO acceptance 2 days before GDS TO

Backend/ P&R	]





## **Test & Product Engineering**

- DFT methodology
  - Highest test and fault coverage
- High speed tests at wafer and module
  - Process
  - Automated test vector translation
  - VLSI and product qualification
  - Burn-in and ESD tests
  - Delay and transition fault speed sorting

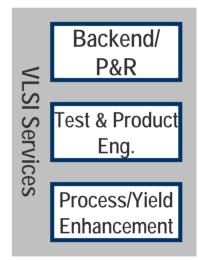
۷L	Backend/ P&R
LSI Services	Test & Product Eng.





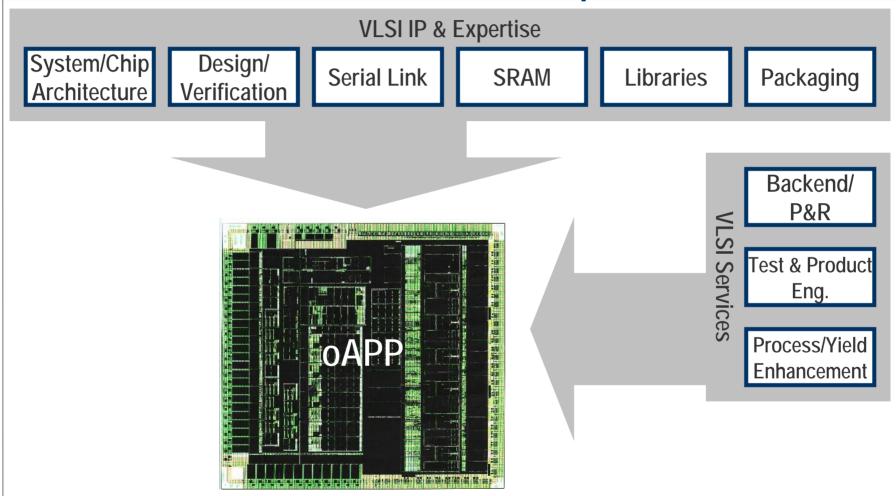
#### **Process/Yield Enhancement**

- Yield calculation/enhancement and FA
- Tune process
- Bit mapping and analysis of all RAMs
- Process/speed monitoring
- Data correlation
- Yield tracing





## oAPP – Procket VLSI COT Development





## PROCKET<sup>M</sup> NETWORKS